

Day: Monday Date: 3/19/2007 Time: 09:18:40

Inventor Name Search Result

Your Search was:

Last Name = TSUCHIYA

First Name = HIDEO

72					
Application#	Patent#	Status	Date Filed	Title	Inventor Name
07709020	Not Issued	166		METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	TSUCHIYA, HIDEO
07941197	5475766	150	09/04/1992	PATTERN INSPECTION APPARATUS WITH CORNER ROUNDING OF REFERENCE PATTERN DATA	TSUCHIYA, HIDEO
08025317	5577171	150	03/02/1993	FIGURE PATTERN GENERATING APPARATUS FOR DETECTING PATTERN DEFECTS	TSUCHIYA, HIDEO
08040852	5379348	150	03/31/1993	PATTERN DEFECTS INSPECTION SYSTEM	TSUCHIYA, HIDEO
08099409	Not Issued	166		METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	TSUCHIYA, HIDEO
08180813	5404410	150	01/10/1994	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	TSUCHIYA, HIDEO
08278141	Not Issued	161	07/21/1994	NON-WOVEN FABRIC AND METHOD OF PRODUCING THE SAME	TSUCHIYA, HIDEO
08413704	5960106	150	03/30/1995	SAMPLE INSPECTION APPARATUS AND SAMPLE INSPECTION METHOD	TSUCHIYA, HIDEO
08561390	5733625	150	11/21/1995	NON-WOVEN FABRIC	TSUCHIYA, HIDEO
08614063	5744381	150	03/12/1996	METHOD OF INSPECTING A PATTERN FORMED ON A SAMPLE FOR A DEFECT, AND AN APPARATUS THEREOF	TSUCHIYA, HIDEO
08937156	6285783	150	09/25/1997	PATTERN DATA GENERATING APPARATUS AND METHOD FOR INSPECTING DEFECTS IN FINE PATTERNS IN A PHOTOMASK OR SEMICONDUCTOR WAFER	TSUCHIYA, HIDEO
10106344	7020321	150	03/27/2002	PATTERN DATA CONVERTING METHOD AND APPARATUS	TSUCHIYA, HIDEO
10252718	6883160	150	09/24/2002	PATTERN INSPECTION APPARATUS	TSUCHIYA, HIDEO

10627702	7068364	150	07/28/2003	PATTERN INSPECTION APPARATUS	TSUCHIYA, HIDEO
10642760	Not Issued	71	08/19/2003	Pattern inspection apparatus	TSUCHIYA, HIDEO
10743830	Not Issued	25		Pattern inspecting method and pattern inspecting apparatus	TSUCHIYA, HIDEO
11079338	Not Issued	95	03/15/2005	PATTERN INSPECTION APPARATUS	TSUCHIYA, HIDEO
11265180	Not Issued	71	11/03/2005	Workpiece inspection apparatus assisting device, workpiece inspection method and computer-readable recording media storing program therefor	TSUCHIYA, HIDEO
11674025	Not Issued	20	02/12/2007	PATTERN INSPECTION APPARATUS •	TSUCHIYA, HIDEO

Inventor Search Completed: No Records to Display.

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Day: Monday Date: 3/19/2007 Time: 09:18:51

Inventor Name Search Result

Your Search was:

Last Name = YAMASHITA

First Name = KYOJI

		[
Application#		==			Inventor Name
07291276	<u>4988197</u>	150		METHOD AND APPARATUS FOR ALIGNING TWO OBJECTS, AND METHOD AND APPARATUS FOR PROVIDING A DESIRED GAP BETWEEN TWO OBJECTS	YAMASHITA, KYOJI
07538186	5100234	150	06/13/1990	METHOD AND APPARATUS FOR ALIGNING TWO OBJECTS, AND METHOD AND APPARATUS FOR PROVIDING A DESIRED GAP BETWEEN TWO OBJECTS	YAMASHITA, KYOJI
07653236	5185812	150	02/11/1991	OPTICAL PATTERN INSPECTION SYSTEM	YAMASHITA, KYOJI
07709020	Not Issued	166	05/31/1991	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	ҮАМАЅНІТА, КҮОЛ
08099409	Not Issued	166	07/30/1993	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	YAMASHITA, KYOJI
08180813	5404410	150	01/10/1994	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	YAMASHITA, KYOJI
08415928	5675168	150	04/03/1995	UNSYMMETRICAL MOS DEVICE HAVING A GATE INSULATOR AREA OFFSET FROM THE SOURCE AND DRAIN AREAS, AND ESD PROTECTION CIRCUIT INCLUDING SUCH A MOS DEVICE	YAMASHITA, KYOJI
08494384	5610430	150	06/26/1995	SEMICONDUCTOR DEVICE HAVING REDUCED GATE OVERLAPPING CAPACITANCE	YAMASHITA, KYOJI
08527902	Not Issued	161	09/14/1995	PHOTO-MASK INSPECTION APPARATUS AND METHOD	YAMASHITA, KYOJI
08664957	5841173	150	06/13/1996	MOS SEMICONDUCTOR DEVICE WITH EXCELLENT DRAIN CURRENT	YAMASHITA, KYOJI
08685726	6281562	150	07/24/1996	A SEMICONDUCTOR DEVICE WHICH REDUCES THE MINIMUM DISTANCE REQUIREMENTS BETWEEN ACTIVE	YAMASHITA, KYOJI

				AREAS	
08687625	5844809	150		METHOD AND APPARATUS FOR GENERATING TWO-DIMENSIONAL CIRCUIT PATTERN	YAMASHITA, KYOJI
08716571	5879983	150		SEMICONDUCTOR DEVICE AND METHOD FOR MANUFACTURING THE SAME	YAMASHITA, KYOJI
08763801	<u>5856754</u>	150		SEMICONDUCTOR INTEGRATED CIRCUIT WITH PARALLELL/SERIAL/PARALLELL CONVERSION	YAMASHITA, KYOJI
08767486	Not Issued	161		SEMICONDUCTOR DEVICE HAVING REDUCED GATE OVERLAPPING CAPACITANCE	YAMASHITA, KYOJI
09092396	6205570	150	1	METHOD FOR DESIGNING LSI CIRCUIT PATTERN	YAMASHITA, КҮОЛ
09112641	6084716	150		OPTICAL SUBSTRATE INSPECTION APPARATUS	YAMASHITA, КҮОЛ
09158086	6396943	150	11	DEFECT INSPECTION METHOD AND DEFECT INSPECTION APPARATUS	YAMASHITA, KYOJI
09166904	6594598	150.	III 1	METHOD FOR CONTROLLING PRODUCTION LINE	YAMASHITA, KYOJI
09192536	6124160	150		SEMICONDUCTOR DEVICE AND METHOD FOR MANUFACTURING THE SAME	YAMASHITA, KYOJI
09629861	6492672	150	08/01/2000	SEMICONDUCTOR DEVICE	YAMASHITA, KYOJI
09902157	6709950	150		SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME	YAMASHITA, KYOJI
09960355	Not Issued	161	09/24/2001	Defect inspection apparatus and method	YAMASHITA, KYOJI
10232689	6876208	150	II .	SEMICONDUCTOR DEVICE AND METHOD OF CHECKING SEMICONDUCTOR STORAGE DEVICE	YAMASHITA, KYOJI
10252718	6883160	150	09/24/2002	PATTERN INSPECTION APPARATUS	YAMASHITA, KYOJI
10355068	6894520	150	01/31/2003	SEMICONDUCTOR DEVICE AND CAPACITANCE MEASUREMENT METHOD	YAMASHITA, KYOJI
10395342	7032208	150	03/25/2003	DEFECT INSPECTION APPARATUS	YAMASHITA, KYOJI
10454682	6967409	150	06/05/2003	SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE	YAMASHITA, KYOJI

				SAME	
10642760	Not Issued	71	08/19/2003	Pattern inspection apparatus	YAMASHITA, KYOJI
10760449	Not Issued	93	11	CAPACITANCE MEASUREMENT CIRCUIT	YAMASHITA, KYOJI
10777068	6982555	150	02/13/2004	SEMICONDUCTOR DEVICE	YAMASHITA, KYOJI
10991457	Not Issued	40	II I	Method for evaluating semiconductor device	YAMASHITA, KYOJI
10995283	7126174	150		SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME	YAMASHITA, KYOJI
11079338	Not Issued	95	03/15/2005	PATTERN INSPECTION APPARATUS	YAMASHITA, KYOJI
11080456	Not Issued	71		Method for variability constraints in design of integrated circuits especially digital circuits which includes timing closure upon placement and routing of digital circuit or network	YAMASHITA, KYOJI
11081679	Not Issued	161	03/17/2005	Semiconductor device and method of manufacturing the same	ҮАМАЅНІТА, КҮОЛ
11101466	Not Issued	30	04/08/2005	Semiconductor integrated circuit design method, design support system for the same, and delay library	YAMASHITA, KYOJI
11138499	7171640	150	05/27/2005	SYSTEM AND METHOD FOR OPERATION VERIFICATION OF SEMICONDUCTOR INTEGRATED CIRCUIT	YAMASHITA, КҮОЛ
11148208	Not Issued	30	06/09/2005	Semiconductor device	YAMASHITA, KYOJI
11202210	Not Issued	30	08/12/2005	Semiconductor device and layout design method for the same	YAMASHITA, KYOJI
11270602	Not Issued	30	11/10/2005	Semiconductor device and method for fabricating the same	YAMASHITA, KYOJI
11270662	Not Issued	71	11/10/2005	Semiconductor integrated circuit and method for designing the same	YAMASHITA, KYOJI
11287419	Not Issued	30	11/28/2005	Sample inspection apparatus, image alignment method, and program-recorded readable recording medium	YAMASHITA, KYOJI
11334506	Not Issued	30	01/19/2006	Semiconductor integrated circuit designing method and library designing method	YAMASHITA, KYOJI
11349077	Not Issued	25	02/08/2006	Circuit simulation method and circuit simulation apparatus	YAMASHITA, KYOJI
<u>11518199</u>	Not	30	09/11/2006	Design method for semiconductor integrated	YAMASHITA, KYOJI

	Issued			circuit	
11553711	Not Issued	25		DATA SEARCHING SYSTEM, METHOD OF SYNCHRONIZING METADATA AND DATA SEARCHING APPARATUS	YAMASHITA, KYOJI
11591452	Not Issued	25		Semiconductor circuit device and design method therefor	YAMASHITA, KYOJI
11674025	Not Issued	20	02/12/2007	PATTERN INSPECTION APPARATUS	YAMASHITA, KYOJI
11678748	Not Issued	17	02/26/2007	TARGET WORKPIECE INSPECTION APPARATUS, IMAGE ALIGNMENT METHOD, AND COMPUTER- READABLE RECORDING MEDIUM WITH PROGRAM RECORDED THEREON	YAMASHITA, KYOJI

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Inventor Name Search Result

Your Search was:

Last Name = WATANABE

First Name = TOSHIYUKI

Application#					Inventor Name
<u>06075661</u>	4268665	150		DERIVATIVES OF ANTIBIOTIC TYLOSIN	WATANABE, TOSHIYUKI
06091663	4264723	150		SILVER HALIDE COLOR PHOTOGRAPHIC MATERIALS	WATANABE, TOSHIYUKI
06104999	4282312	150	12/18/1979	COLOR IMAGE FORMING PROCESS	WATANABE, TOSHIYUKI
06126934	4310619	150	03/03/1980	COLOR PHOTGRAPHIC MATERIAL AND PROCESS INCORPORATING A NOVEL MAGENTA COUPLER	WATANABE, TOSHIYUKI
06168616	Not Issued	161	07/14/1980	AIR CONTROL ATTACHMENT FOR THE FRONT OF A VEHICLE, OR SIMILAR ARTICLE	WATANABE, TOSHIYUKI
06168617	Not Issued	161	07/14/1980	AIR CONTROL ATTACHMENT FOR THE REAR OF A VEHICLE, OR SIMILAR ARTICLE	WATANABE, TOSHIYUKI
06168618	D267864	150	07/14/1980	MUDGUARD FOR A VEHICLE, OR SIMILAR ARTICLE	WATANABE, TOSHIYUKI
06216714	4310623	150	12/15/1980	COLOR PHOTOGRAPHIC LIGHT- SENSITIVE MATERIAL	WATANABE, TOSHIYUKI
06243159	4407936	150	03/12/1981	PROCESS AND MATERIAL FOR FORMING COLOR PHOTOGRAPHIC IMAGE	WATANABE, TOSHIYUKI
06326208	Not Issued	166	12/01/1981	ORAL COMPOSITION	WATANABE, TOSHIYUKI
06356076	4454521	150	03/08/1982	DIAZO-TYPE THERMOSENSITIVE RECORDING MATERIAL	WATANABE, TOSHIYUKI
06412406	Not Issued	161	08/27/1982	DIAZO-TYPE THERMOSENSITIVE RECORDING MATERIAL	WATANABE, TOSHIYUKI
06440044	4411987	150	11/08/1982	SILVER HALIDE COLOR PHOTOGRAPHIC LIGHT-SENSITIVE MATERIAL	WATANABE, TOSHIYUKI
06496289	Not Issued	166	05/19/1983	RETURNABLE BOX	WATANABE, TOSHIYUKI

06497636	4522915	150		COLOR PHOTOGRAPHIC SILVER HALIDE LIGHT-SENSITIVE MATERIALS CONTAINING NOVEL MAGENTA COLOR-FORMING COUPLERS	WATANABE, TOSHIYUKI
06516869	Not Issued	161	07/26/1983	ORAL COMPOSITION	WATANABE, TOSHIYUKI
06537609	4532807	150		METHOD AND APPARATUS FOR DETECTING SOUND SOURCE	WATANABE, TOSHIYUKI
06571762	Not Issued	161		SILVER HALIDE COLOR PHOTOGRPHIC LIGHT-SENSITIVE MATERIALS	WATANABE, TOSHIYUKI
06572048	4567135	150		SILVER HALIDE COLOR PHOTOGRAPHIC LIGHT-SENSITIVE MATERIAL	WATANABE, TOSHIYUKI
06572049	4536472	150	01/19/1984	SILVER HALIDE COLOR PHOTOGRAPHIC LIGHT-SENSITIVE MATERIAL	WATANABE, TOSHIYUKI
06636290	4630813	150		METHOD OF AND DEVICE FOR DETECTING DISPLACEMENT OF PAPER SHEETS	WATANABE, TOSHIYUKI
06645148	4579813	150	08/28/1984	SILVER HALIDE COLOR PHOTOGRAPHIC MATERIALS	WATANABE, TOSHIYUKI
06667445	4589768	150	11/01/1984	ORIGINAL TRANSFER APPARATUS	WATANABE, TOSHIYUKI
06696545	4578346	150	01/30/1985	SILVER HALIDE COLOR PHOTOGRAPHIC LIGHT-SENSITIVE MATERIALS	WATANABE, TOSHIYUKI
06797194	Not Issued	166	11/13/1985	RETURNABLE BOX	WATANABE, TOSHIYUKI
06855299	Not Issued	161	04/24/1986	TITANIUM ALLOYS HAVING AN EXCELLENT COLD WORKABILITY	WATANABE, TOSHIYUKI
06869805	Not Issued	161	05/29/1986	RETURNABLE BOX	WATANABE, TOSHIYUKI
06901224	4764456	150	08/28/1986	SILVER HALIDE COLOR PHOTOGRAPHIC MATERIAL	WATANABE, TOSHIYUKI
06906311	4785862	150	09/11/1986	DUAL TIRE MOUNTING METHOD	WATANABE, TOSHIYUKI
06917092	Not Issued	166	11/24/1986	SILVER HALIDE PHOTOGRAPHIC LIGHT-SENSITIVE MATERIAL	WATANABE, TOSHIYUKI
06947302	4783397	150	12/29/1986	SILVER HALIDE COLOR PHOTOGRAPHIC MATERIAL CONTAINING A COUPLER FOR FORMING A YELLOW DYE, AND A PROCESS FOR PRODUCING YELLOW	WATANABE, TOSHIYUKI

				IMAGES USING THE SAME	1
07003773	4735288	150		DETACHABLY ATTACHING MECHANISM FOR CUP OF LUBRICATOR OR FILTER USED WITH AIR-ACTUATED DEVICE	WATANABE, TOSHIYUKI
07052881	4874689	150		SILVER HALIDE COLOR PHOTOGRAPHIC MATERIAL	WATANABE, TOSHIYUKI
07088318	Not Issued	161		LIGHT-SENSITIVE MATERIAL CONTAINING SILVER HALIDE, REDUCING AGENT AND POLYMERIZABLE COMPOUND	WATANABE, TOSHIYUKI
07102193	4892681	250	09/29/1987	NON-LINEAR OPTICAL ARTICLE	WATANABE, TOSHIYUKI
07109886	Not Issued	166 ·		LIGHT-SENSITIVE MATERIAL CONTAINING SILVER HALIDE, REDUCING AGENT AND POLYMERIZABLE COMPOUND	WATANABE, TOSHIYUKI
07115064	4775656	150		RECORDING MATERIAL CONTAINING LEUCO DYE	WATANABE, TOSHIYUKI
07115067	Not Issued	166		LIGHT-SENSITIVE MATERIAL CONTAINING SILVER HALIDE, REDUCING AGENT AND POLYMERIZABLE COMPOUND	WATANABE, TOSHIYUKI
07122807	Not Issued	166	11/19/1987	LIGHT-SENSITIVE MATERIAL CONTAINING SILVER HALIDE, REDUCING AGENT AND POLYMERIZABLE COMPOUND	WATANABE, TOSHIYUKI
<u>07199078</u>	4844568	150	05/26/1988	SCANNING TYPE PROJECTION EXPOSURE SYSTEM	WATANABE, TOSHIYUKI
07199635	4997741	150	05/27/1988	COLOR IMAGE FORMING METHOD USING LEUCO DYES AND RECORDING MATERIAL CONTAINING LEUCO DYES	WATANABE, TOSHIYUKI
07309905	4925782	150	02/13/1989	SILVER HALIDE PHOTOGRAPHIC LIGHT-SENSITIVE ELEMENT CONTAINING WATER SOLUBLE DYE COMPOUNDS	WATANABE, TOSHIYUKI
07350684	D315758	150	05/10/1989	TOY AIRPLANE COCKPIT	WATANABE, TOSHIYUKI
07362464	5045239	250	03/17/1989	NON-LINEAR OPTICAL MATERIAL	WATANABE, TOSHIYUKI
07373131	5110988	150	06/29/1989	NONLINEAR OPTICAL MATERIAL	WATANABE, TOSHIYUKI
07391663	4959291	150		LIGHT-SENSITIVE MATERIAL CONTAINING SILVER HALIDE,	WATANABE, TOSHIYUKI

				REDUCING AGENT, POLYMERIZABLE COMPOUND AND A DIAZAPHTHALIDE DYE	
07489752	Not Issued	161	02/26/1990		WATANABE, TOSHIYUKI
07565088	Not Issued	166	08/10/1990	SILVER HALIDE PHOTOGRAPHIC LIGHT-SENSITIVE MATERIALS	WATANABE, TOSHIYUKI
07604400	5030543	150		LIGHT-SENSITIVE MATERIAL CONTAINING SILVER HALIDE, REDUCING AGENT AND POLYMERIZABLE COMPOUND	WATANABE, TOSHIYUKI
07621427	5159483	150	12/05/1990		WATANABE, · TOSHIYUKI

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Inventor Name Search Result

Your Search was:

Last Name = ISOMURA First Name = IKUNAO

Application#	Patent#				Inventor Name
08937156	6285783	150	09/25/1997	PATTERN DATA GENERATING APPARATUS AND METHOD FOR INSPECTING DEFECTS IN FINE PATTERNS IN A PHOTOMASK OR SEMICONDUCTOR WAFER	ISOMURA, IKUNAO
10642760	Not Issued	71	08/19/2003	Pattern inspection apparatus	ISOMURA, IKUNAO
10720136	Not Issued	30	11/25/2003	Pattern inspection apparatus	ISOMURA, IKUNAO
10809409	Not Issued	71	03/26/2004	Pattern inspection apparatus	ISOMURA, IKUNAO
11072317	Not Issued	30	03/07/2005	Defect inspection apparatus and defect inspection method	ISOMURA, IKUNAO
11083202	Not Issued	41	03/18/2005	Mask defect inspection apparatus	ISOMURA, IKUNAO
11083323	Not Issued	30	03/18/2005	Mask-defect inspecting apparatus	ISOMURA, IKUNAO
11175360	Not Issued	30	07/07/2005	Pattern inspecting method	ISOMURA, IKUNAO
11276426	Not Issued	30	02/28/2006	PATTERN INSPECTION APPARATUS, PATTERN INSPECTION METHOD AND PROGRAM	ISOMURA, IKUNAO
11283755	Not Issued	25	11/22/2005	Pattern inspection apparatus, pattern inspection method, and program-recorded readable recording medium	ISOMURA, IKUNAO
11284186	Not Issued	30	11/22/2005	Pattern inspection apparatus, pattern inspection method, and program-recorded readable recording medium	ISOMURA, IKUNAO
11674025	Not Issued	20	02/12/2007	PATTERN INSPECTION APPARATUS	ISOMURA, IKUNAO

Inventor Search Completed: No Records to Display.

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Day: Monday Date: 3/19/2007 Time: 09:19:50

Inventor Name Search Result

Your Search was:

Last Name = TOJO

First Name = TORU

Application#	Patent#	Status	Date Filed	Title	Inventor Name
	4262974				TOJO, TORU
06250386	4408126	150	1	CASSETTE RETAINING DEVICE OF ELECTRON BEAM APPARATUS	TOJO, TORU
06374724	4469949	150	05/04/1982	ELECTRON BEAM PATTERN TRANSFER DEVICE AND METHOD FOR ALIGNING MASK AND SEMICONDUCTOR WAFER	TOJO, TORU
06379712	4467210	150	05/19/1982	ELECTRON-BEAM IMAGE TRANSFER DEVICE	TOJO, TORU
06428341	4480284	150	09/29/1982	ELECTROSTATIC CHUCK PLATE	TOJO, TORU
06429230	4455501	150	09/30/1982	PRECISION ROTATION MECHANISM	TOJO, TORU
06495486	4532423	150	05/17/1983	IC TESTER USING AN ELECTRON BEAM CAPABLE OF EASILY SETTING A PROBE CARD UNIT FOR WAFERS AND PACKAGED IC'S TO BE TESTED	TOJO, TORU
06525419	4572956	150	08/22/1983	ELECTRON BEAM PATTERN TRANSFER SYSTEM HAVING AN AUTOFOCUSING MECHANISM	TOJO, TORU
06527486	4558225	150	08/29/1983	TARGET BODY POSITION MEASURING METHOD FOR CHARGED PARTICLE BEAM FINE PATTERN EXPOSURE SYSTEM	TOJO, TORU
06664964	4578607	150	10/26/1984	PIEZOELECTRIC PRECISE ROTATION MECHANISM FOR SLIGHTLY ROTATING AN OBJECT	TOJO, TORU
06789086	Not Issued	166	10/18/1985	POSITION DETECTOR BY VIBRATING A LIGHT BEAM FOR AVERAGING THE REFLECTED LIGHT	TOJO, TORU
07009628	4698513	150	01/23/1987	POSITION DETECTOR BY VIBRATING	TOJO, TORU

71.0					
-				A LIGHT BEAM FOR AVERAGING THE REFLECTED LIGHT	
07012282	Not Issued	166		METHOD FOR ALIGNING FIRST AND SECOND OBJECTS RELATIVE TO EACH OTHER, AND APPARATUS FOR PRACTICING THIS METHOD	TOJO, TORU
07051709	Not Issued	161		METHOD FOR TRANSFERRING PATTERNS AND APPARATUS FOR TRANSFERRING PATTERNS	TOJO, TORU
07167233	4808002	150	03/11/1988	METHOD AND DEVICE FOR ALIGNING FIRST AND SECOND OBJECTS RELATIVE TO EACH OTHER	TOJO, TORU
07214821	4811062	150	•	METHOD FOR ALIGNING FIRST AND SECOND OBJECTS RELATIVE TO EACH OTHER AND APPARATUS FOR PRACTICING THIS METHOD	TOJO, TORU
07251842	4902133	150	09/30/1988	METHOD AND AN APPARATUS FOR ALIGNING FIRST AND SECOND OBJECTS WITH EACH OTHER	TOJO, TORU
<u>07453856</u>	4984890	150	12/20/1989	METHOD AND AN APPARATUS FOR ALIGNING FIRST AND SECOND OBJECTS WITH EACH OTHER	TOJO, TORU
07709020	Not Issued	166	05/31/1991	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	TOJO, TORU
08040852	5379348	150	03/31/1993	PATTERN DEFECTS INSPECTION SYSTEM	TOJO, TORU
08099409	Not Issued	166	07/30/1993	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	TOJO, TORU
08180813	5404410	150	01/10/1994	METHOD AND SYSTEM FOR GENERATING A BIT PATTERN	TOJO, TORU
08413174	Not Issued	166	03/29/1995	SAMPLE INSPECTION APPARATUS AND SAMPLE INSPECTION METHOD	TOJO, TORU
08413704	5960106	150	03/30/1995	SAMPLE INSPECTION APPARATUS AND SAMPLE INSPECTION METHOD	TOJO, TORU
08527633	5602645	150	09/13/1995	PATTERN EVALUATION APPARATUS AND A METHOD OF PATTERN EVALUATION	TOJO, TORU
08614063	5744381			METHOD OF INSPECTING A PATTERN FORMED ON A SAMPLE FOR A DEFECT, AND AN APPARATUS THEREOF	TOJO, TORU
08748898	5812259	150	11/15/1996	METHOD AND APPARATUS FOR	TOJO, TORU

				INSPECTING SLIGHT DEFECTS IN A PHOTOMASK PATTERN	
08841762	5912468	150	04/28/1997	CHARGED PARTICLE BEAM EXPOSURE SYSTEM	TOJO, TORU
08854750	5828457	150	05/12/1997	SAMPLE INSPECTION APPARATUS AND SAMPLE INSPECTION METHOD	TOJO, TORU
09038037	6090176	150		SAMPLE TRANSFERRING METHOD AND SAMPLE TRANSFER SUPPORTING APPARATUS	TOJO, TORU
09038038	6182369	150	03/11/1998	PATTERN FORMING APPARATUS	TOJO, TORU
09040286	6239443	150	03/18/1998	APPARATUS FOR EMITTING A BEAM TO A SAMPLE USED FOR MANUFACTURING A SEMICONDUCTOR DEVICE	TOJO, TORU
09040391	6080990	150	03/18/1998	POSITION MEASURING APPARATUS	TOJO, TORU
09112641	6084716	150		OPTICAL SUBSTRATE INSPECTION APPARATUS	TOJO, TORU
09274304	Not Issued	161	03/23/1999	SEMICONDUCTOR SUBSTRATE TRANSPORT SYSTEM UTILIZING LOCAL CLEANING TECHNOLOGY	TOJO, TORU
09496643	6411023	150	02/03/2000	VACUUM PROCESSING APPARATUS AND ION PUMP CAPABLE OF SUPPRESSING LEAKAGE OF IONS AND ELECTRONS FROM ION PUMP	TOJO, TORU
09533265	6346354	150	03/20/2000	Pattern writing method	TOJO, TORU
09562181	6281510	150	05/02/2000	Sample transferring method and sample transfer supporting apparatus	TOJO, TORU
09933719	6676289	150	08/22/2001	TEMPERATURE MEASURING METHOD IN PATTERN DRAWING APPARATUS	TOJO, TORU
10397288	6901314	150	03/27/2003	ALIGNMENT APPARATUS FOR SUBSTRATES	TOJO, TORU
10642760	Not Issued	71	08/19/2003	Pattern inspection apparatus	TOJO, TORU
10720136	Not Issued	30	11/25/2003	Pattern inspection apparatus	TOJO, TORU
10809409	Not Issued	71	03/26/2004	Pattern inspection apparatus	TOJO, TORU
10852434	Not Issued	41	05/25/2004	Inspection apparatus having two sensors, method for inspecting an object, and a	TOJO, TORU

	.]			method for manufacturing a photolithography mask	
10897120	7123345	150	07/23/2004	AUTOMATIC FOCUSING APPARATUS	TOJO, TORU
11012257	7075621	150	12/16/2004	ALIGNMENT METHOD	TOJO, TORU
11072317	Not Issued	30	03/07/2005	Defect inspection apparatus and defect inspection method	TOJO, TORU
11175360	Not Issued	30	07/07/2005	Pattern inspecting method	TOJO, TORU
11248124	Not Issued	30		Defect inspecting apparatus and defect inspection method	TOJO, TORU
11249359	Not Issued	30	10/14/2005	Defect inspecting apparatus	TOJO, TORU

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Last Name = SANADA First Name = YASUSHI

Application#	Patent#	Status	Date Filed	Title	Inventor Name
09112641	6084716	150	07/09/1998	OPTICAL SUBSTRATE INSPECTION APPARATUS	SANADA, YASUSHI
09956010	6909501	150		PATTERN INSPECTION APPARATUS AND PATTERN INSPECTION METHOD	SANADA, YASUSHI
10627702	7068364	150	07/28/2003	PATTERN INSPECTION APPARATUS	SANADA, YASUSHI
10642760	Not Issued	71	08/19/2003	Pattern inspection apparatus	SANADA, YASUSHI
10743830	Not Issued	25	12/24/2003	Pattern inspecting method and pattern inspecting apparatus	SANADA, YASUSHI
11444488	Not Issued	30	06/01/2006	Battery pack of assembled battery and fixing method of assembled battery	SANADA, YASUSHI
11444492	Not Issued	25	06/01/2006	Battery pack	SANADA, YASUSHI
11674025	Not Issued	20	02/12/2007	PATTERN INSPECTION APPARATUS	SANADA, YASUSHI

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